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DEPARTMENT OF BIOENGINEERING 94720-1762

BioE 121

Midterm #1 Solutions

Problem #1. (20 points) Photolithography

- a. (5 points) Describe basic photochemical mechanism of a positive resist (DQN)
- b. (10 points) Describe the photochemical mechanism of reverse image process of a positive resist.
- c. (5 points) Compare optical and e-beam lithography methods (resolutions limit, process time, cost, etc)

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a)
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BioMEMS

b)



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BioMEMS

e-beam Lithography:

Advantage:

Very small beam spot (< 1nm), can define very small features

Disadvantages:

Low throughput – a serial writing process versus the parallel writing process of optical lithography.

Proximity effect- Backscattered electrons from substrate material may affect critical feature size.



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Problem #2. (20 points) Sacrificial Layer Process

- a. (10 points). Figure 1 show an encapsulated cantilever in the air. Show the process steps to accomplish this device by cross sectional fabrication steps
- b. (10 points). Describe deposition and etching methods for each step



Figure 1

i) - CVD Deposition of Phosphosilicate glass (PSG)
- CVD Deposition and Patterning of Polysilicon



ii) CVD Deposition of Phosphosilicate glass (PSG)





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iii) Ion beam etching (Ion Milling) of PSG



iv) CVD Deposition of Polysilicon



v) Release the structure by HF etch



Note: This proposed fabrication process is the easiest method to get the desired topology, although, ion beam etching is not a common used method in micro fabrication technology. One other method, is using two different wafers and bond them together to get the desired topology bowever this method cost much more than the proposed process flow.

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Problem #3. (20 points) Fabrication Process

In your old laboratory, you have only simple plasma-etching system and chemicals (KOH, Water, Isopropyl alcohol, HNO₃, HF, and HC₂H₃O₂). Select which you would use in the following applications. Be sure to justify your answer with an estimated etching rate. If you need to use the plasma-etching system, make sure to indicate what kind of gas you need to etch properly.

- a. (3 points) Thin film etching of Si_3N_4
- b. (3 points) Sacrificial oxide (PSG) layer etching under 700 nm polysilicon layer
- c. (3 points) Anisotropic patterning of SiO₂.
- d. (3 points) Selective etching of doped Si membrane
- e. (3 points) Explain the mechanism of deep RIE
- f. (5points) You need to find a process step that requires to pattern 10 microns width of a metal thin film on 10 nm thicknesses of SiO₂. Your chip design requires to maintain 10 nm of SiO₂ without any damage. However, your dry etching system for the metal is also etching SiO₂. Unfortunately, dry etching system that you have for metal does not have a selective etching rate for metal over SiO₂, it is hard to stop on 10 nm thickness of SiO₂. What is a simple and effective method of micropatterning the metal layer on SiO₂ without damaging SiO₂ layer? Explain your process steps in details.
 - a) Non of the given chemicals will etch Si_3N_4 . Use plasma etching (SF₆ + He) which has etch rate of ~ 0.6 μ m/min
 - b) Use HF : etch rate ~ 0.165 μ m/min
 - c) Plasma Etch with $CF_4 + O_2$: etch rate ~ 0.06 μ m/min
 - d) Use KOH to selectively etch undoped Si : etch rate ~ 1.4 μ m/min
 - e) DRIE (Deep Reactive Ion Etching) alternates between isotropic Reactive Ion Etching (RIE) and polymer deposition. An inducing coupled plasma is source of deposition. The polymer protects the side wall as the bottom of the cavity is etched further. With this method high aspect ration is attained.





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Problem #4. (20 points) Oligonucleotide Arrays

- a. (5 points) Describe the fabrication steps of ologinucleotide arrays of following base pairs: TACG, CATA, ATTA, GAGG, and TATA on a substrate.
- b. (5 points) Describe the detection methods of current ologinucleotide probes and discuss the limitation.
- c. (5 points) Compare direct and indirect methods of detecting DNA sequencing.
- d. (5 points) Describe a method of measuring a bonding force between base pairs of DNA using AFM tip.

a)



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TECI-INOLOGIES

b) Fluorescently-tagged probes, when hybridized with the correct complementary sample DNA bases, will emit light when it is excited with laser (usually of shorter wavelength). Many limitations: expensive, elaborate optical equipment, only work with short oligonucleotide probes (20-25 base pairs).

c) Direct method: nanoprobe – directly sensing individual bases on a string, researchers are working in this area using nanopores.

Indirect methods: Oligonucleotide probe arrays, northern blot, southern blot, PCR-dot blot: slow, expensive, but well-established and reliable methods

d) Photolysis:





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Problem #5. (20 points) Surface & Bulk Micromachining Process: Self Focusing Acoustic Transducer (SFAT) for DNA or Protein Array

- a. (10 points). Figure 2 show the SFAT. The SFAT can be used as a liquid ejector and it is fabricated by silicon micromachining. Show the process steps to accomplish this device by cross sectional fabrication steps
- b. (10 points). Describe deposition and etching methods for each step



Figure 2. Cross-sectional view of the liquid ejector microfabricated on a silicon wafer.



Figure 4. Fabrication processing steps for sector SFAT. (a) Deposit $0.8\mu m$ thick Si₈N_y (b) Pattern Si₈N_y at the wafer backside. (c) Deposit and pattern bottom Al electrodes. (d) Sputter-deposit ZnO (e) Deposit and pattern top Al electrodes. (f) Remove the silicon from the backside with the front side protected with a mechanical jig.

A brief fabrication process for the sectored SFAT is illustrated in Fig. 4 and described as follows. After depositing 0.8µm thick LPCVD low stress nitride and patterning the nitride on the wafer backside, 0.5µm thick Al is deposited and patterned for the bottom electrode on the wafer front side. Then, 5µm thick ZnO is sputter deposited from ZnO target, followed by 0.5µm thick Al evaporation and pattering for the top electrodes. Finally, the silicon is removed by KOH from the backside to form 500 x 500 µm² diaphragms, the front side being protected with a mechanical jig against KOH.



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